

# NX3008NBKV

# 30 V, 400 mA dual N-channel Trench MOSFET Rev. 1 — 1 August 2011

Product data sheet

## **Product profile**

#### 1.1 General description

Dual N-channel enhancement mode Field-Effect Transistor (FET) in an ultra small and flat lead SOT666 Surface-Mounted Device (SMD) plastic package using Trench MOSFET technology.

#### 1.2 Features and benefits

- Very fast switching
- Low threshold voltage
- Trench MOSFET technology
- ESD protection up to 2 kV
- AEC-Q101 qualified

#### 1.3 Applications

- Relay driver
- High-speed line driver

- Low-side loadswitch
- Switching circuits

#### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Per transis	stor					
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> = 25 °C	-	-	30	V
V <sub>GS</sub>	gate-source voltage		-8	-	8	V
$I_D$	drain current	$V_{GS} = 4.5 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}$	<u>[1]</u> _	-	400	mA
Static characteristics (per transistor)						
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 350 \text{ mA};$ $T_j = 25 \text{ °C}$	-	1	1.4	Ω

<sup>[1]</sup> Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.



## 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S1	source TR1		D4 D0
2	G1	gate TR1	6 5 4	D1 D2
3	D2	drain TR2		
4	S2	source TR2		$G1 \longrightarrow G2$
5	G2	gate TR2	1 2 3	
6	D1	drain TR1	SOT666 (SOT666)	S1 S2 017aaa256

# 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
NX3008NBKV	SOT666	plastic surface-mounted package; 6 leads	SOT666

## 4. Marking

Table 4. Marking codes

Type number	Marking code <sup>[1]</sup>
NX3008NBKV	AA

<sup>[1] % =</sup> placeholder for manufacturing site code.

## 5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
Per transisto	r					
$V_{DS}$	drain-source voltage	T <sub>j</sub> = 25 °C		-	30	V
$V_{GS}$	gate-source voltage			-8	8	V
I <sub>D</sub>	drain current	$V_{GS} = 4.5 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}$	<u>[1]</u>	-	400	mA
		V <sub>GS</sub> = 4.5 V; T <sub>amb</sub> = 100 °C	<u>[1]</u>	-	260	mA
I <sub>DM</sub>	peak drain current	$T_{amb} = 25 \text{ °C}$ ; single pulse; $t_p \le 10 \text{ µs}$		-	1.6	Α
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = 25 °C	[2]	-	330	mW
			<u>[1]</u>	-	390	mW
		T <sub>sp</sub> = 25 °C		-	1090	mW
Per device						
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = 25 °C	[2]	-	500	mW
Tj	junction temperature			-55	150	°C
T <sub>amb</sub>	ambient temperature			-55	150	°C
T <sub>stg</sub>	storage temperature			-65	150	°C
Source-drain	diode					
Is	source current	T <sub>amb</sub> = 25 °C		-	400	mΑ
ESD maximu	m rating					
V <sub>ESD</sub>	electrostatic discharge voltage	НВМ	[3]	-	2000	V

<sup>[1]</sup> Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.

<sup>[2]</sup> Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.

<sup>[3]</sup> Measured between all pins.

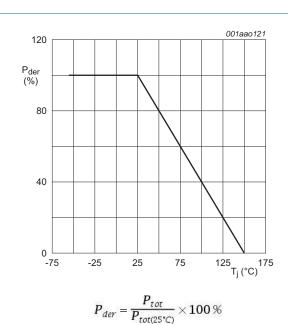


Fig 1. Normalized total power dissipation as a function of junction temperature

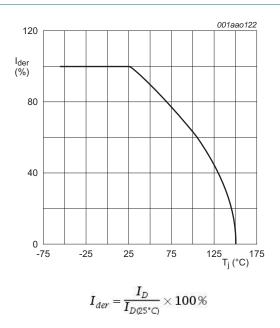
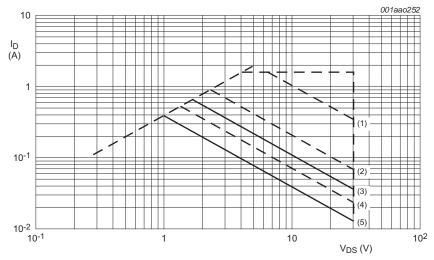


Fig 2. Normalized continuous drain current as a function of junction temperature



I<sub>DM</sub> is a single pulse

(1) 
$$t_p = 1 \text{ ms}$$

(2) 
$$t_p = 10 \text{ ms}$$

(3) DC; 
$$T_{sp} = 25 \, ^{\circ}C$$

(4) 
$$t_p = 100 \text{ ms}$$

(5) DC;  $T_{amb} = 25 \text{ °C}$ ; 1 cm<sup>2</sup> drain mounting pad

Fig 3. Safe operating area; junction to ambient; continuous and peak drain currents as a function of drain-source voltage

#### 6. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Per transistor						
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	in free air	[1] -	330	380	K/W
			[2] _	280	320	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	115	K/W
Per device						
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	[1] -	-	250	K/W

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.

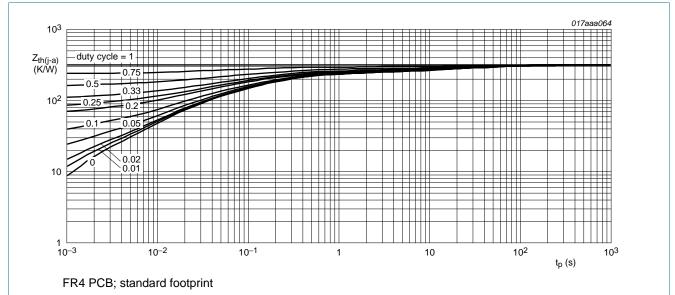


Fig 4. Per transistor: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

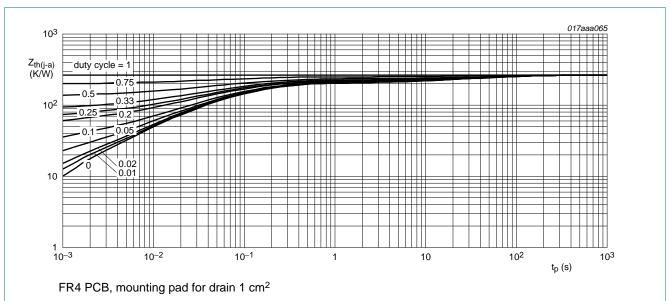


Fig 5. Per transistor: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

## 7. Characteristics

Table 7. Characteristics

Table 7.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics (per transistor)					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
$V_{GSth}$	gate-source threshold voltage	$I_D = 250 \mu A; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	0.6	0.9	1.1	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	10	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	0.2	1	μΑ
		$V_{GS} = -8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.2	1	μΑ
		$V_{GS} = 4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	-	nΑ
		$V_{GS} = -4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	-	nΑ
		$V_{GS} = 2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	1	-	nA
		$V_{GS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	1	-	nΑ
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 350 \text{ mA}; T_j = 25 \text{ °C}$	-	1	1.4	Ω
		$V_{GS} = 4.5 \text{ V}; I_D = 350 \text{ mA}; T_j = 150 \text{ °C}$	-	1.8	2.5	Ω
		$V_{GS} = 2.5 \text{ V}; I_D = 200 \text{ mA}; T_j = 25 \text{ °C}$	-	1.4	2.1	Ω
		$V_{GS} = 1.8 \text{ V}; I_D = 10 \text{ mA}; T_j = 25 \text{ °C}$	-	2	2.8	Ω
9 <sub>fs</sub>	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 350 \text{ mA}; T_j = 25 \text{ °C}$	-	310	-	mS
Dynamic	characteristics (per transist	or)				
Q <sub>G(tot)</sub>	total gate charge	$V_{DS} = 15 \text{ V}; I_D = 400 \text{ mA}; V_{GS} = 4.5 \text{ V};$	-	0.52	0.68	nC
$Q_{GS}$	gate-source charge	$T_j = 25  ^{\circ}C$	-	0.17	-	nC
$Q_{GD}$	gate-drain charge		-	0.08	-	nC
C <sub>iss</sub>	input capacitance	$V_{DS} = 15 \text{ V}; f = 1 \text{ MHz}; V_{GS} = 0 \text{ V};$	-	34	50	pF
C <sub>oss</sub>	output capacitance	$T_j = 25 ^{\circ}\text{C}$	-	6.5	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	2.2	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 20 \text{ V}; R_L = 250 \Omega; V_{GS} = 4.5 \text{ V};$	-	15	30	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 6 \Omega; T_j = 25 °C$	-	11	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	69	138	ns
t <sub>f</sub>	fall time		-	19	-	ns
Source-d	rain diode (per transistor)					
$V_{SD}$	source-drain voltage	$I_S = 350 \text{ mA}; V_{GS} = 0 \text{ V}; T_i = 25 \text{ °C}$	0.47	0.85	1.2	V

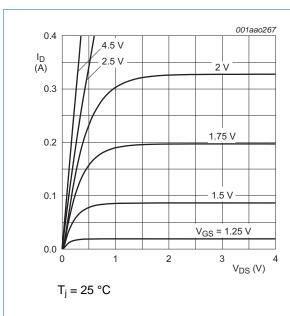
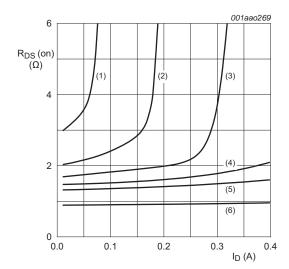


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values



 $T_i = 25 \, ^{\circ}C$ 

(1)  $V_{GS} = 1.5 \text{ V}$ 

(2)  $V_{GS} = 1.75 \text{ V}$ 

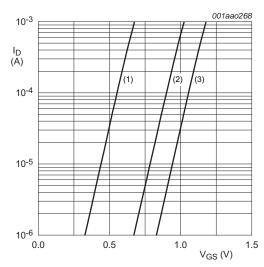
(3)  $V_{GS} = 2.0 \text{ V}$ 

(4)  $V_{GS} = 2.25 \text{ V}$ 

(5)  $V_{GS} = 2.5 \text{ V}$ 

(6)  $V_{GS} = 4.5 \text{ V}$ 

Fig 8. Drain-source on-state resistance as a function of drain current; typical values



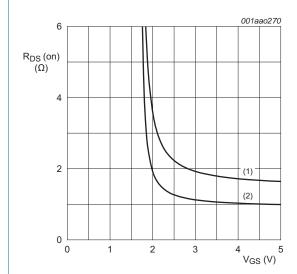
 $T_{j} = 25 \, ^{\circ}C; \, V_{DS} = 5 \, V$ 

(1) minimum values

(2) typical values

(3) maximum values

Fig 7. Sub-threshold drain current as a function of gate-source voltage

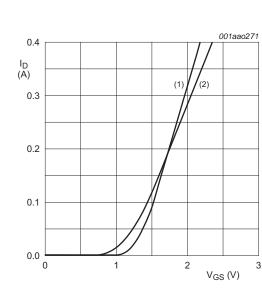


 $I_D = 400 \text{ mA}$ 

(1)  $T_i = 150 \,^{\circ}C$ 

(2)  $T_i = 25 \, ^{\circ}\text{C}$ 



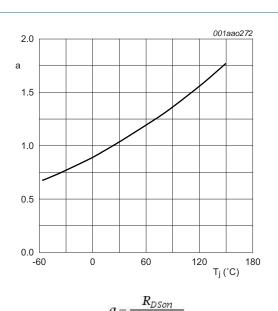


 $V_{DS} > I_D \times R_{DSon}$ 

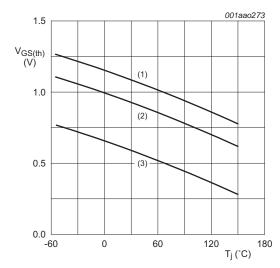
(1) 
$$T_j = 25 \,{}^{\circ}\text{C}$$

(2)  $T_j = 150 \, ^{\circ}\text{C}$ 

Fig 10. Transfer characteristics: drain current as a function of gate-source voltage; typical values



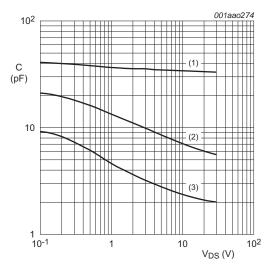




 $I_D = 0.25 \text{ mA}; V_{DS} = V_{GS}$ 

- (1) maximum values
- (2) typical values
- (3) minimum values

Fig 12. Gate-source threshold voltage as a function of junction temperature



 $f = 1 \text{ MHz}; V_{GS} = 0 \text{ V}$ 

(1)C<sub>iss</sub>

(2)Coss

(3)C<sub>rss</sub>

Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

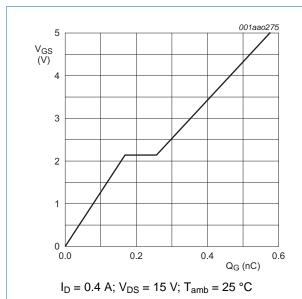


Fig 14. Gate-source voltage as a function of gate charge; typical values

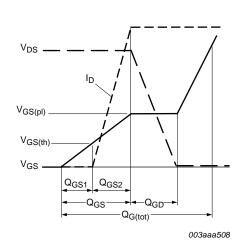
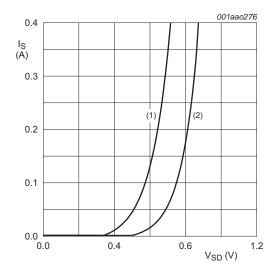


Fig 15. Gate charge waveform definitions



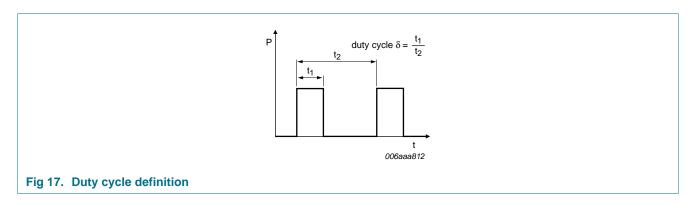
 $V_{GS} = 0 V$ 

(1)  $T_j = 150 \, ^{\circ}C$ 

(2)  $T_i = 25 \, ^{\circ}C$ 

Fig 16. Source current as a function of source-drain voltage; typical values

## 8. Test information



## 8.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

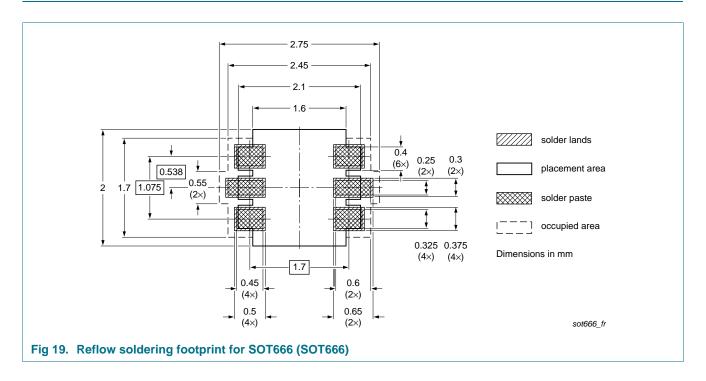
## 9. Package outline

#### Plastic surface-mounted package; 6 leads **SOT666** Α Χ S **→** | w (M) A detail X 2 mm scale DIMENSIONS (mm are the original dimensions) UNIT D Е Α bp e<sub>1</sub> $H_{\mathsf{E}}$ $L_{p}$ у 0.6 0.27 0.18 0.3 1.7 1.3 1.7 0.5 1.0 0.1 0.5 0.17 0.08 1.5 1.5 11 0.1 **REFERENCES** EUROPEAN OUTLINE ISSUE DATE VERSION JEDEC **PROJECTION** IEC JEITA 04-11-08 SOT666 06-03-16

Fig 18. Package outline SOT666 (SOT666)

NX3008NBKV

## 10. Soldering



NXP Semiconductors NX3008NBKV

30 V, 400 mA dual N-channel Trench MOSFET

# 11. Revision history

#### Table 8. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
NX3008NBKV v.1	20110801	Product data sheet	-	-

### 12. Legal information

#### 12.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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#### 30 V, 400 mA dual N-channel Trench MOSFET

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**NXP Semiconductors** 

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#### 14. Contents

1	Product profile
1.1	General description1
1.2	Features and benefits1
1.3	Applications
1.4	Quick reference data1
2	Pinning information2
3	Ordering information2
4	Marking2
5	Limiting values3
6	Thermal characteristics5
7	Characteristics7
8	Test information11
8.1	Quality information
9	Package outline12
10	Soldering13
11	Revision history14
12	Legal information15
12.1	Data sheet status
12.2	Definitions15
12.3	Disclaimers
12.4	Trademarks16
13	Contact information16

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